

A8 Full Automatic Prober

- High precision and test speed, greatly improving test efficiency
- Micron-scale fully closed-loop motion control
- High voltage and high current test application
- Bernoulli arm support sheet
- Small size, light weight, smaller footprint
- 24X7 hours on-chip detection

A12 Full Automatic Prober

- Super high test precision and test speed, greatly improve productivity benefits
- Fully automated system running, fast safe and reliable test
- Support single point testing and continuous testing
- Integrated control system, fast access to instrument testing
- XY maximum speed (screw structure): 250mm/s; XY maximum speed (linear motor): 500mm/s
- Index time (screw structure): 280ms(10mm Die size, 200 μ m separation height); Index time (linear motor): 200ms(5mm Die size, 300 μ m separation height)
- Rich software automation test, precise mechanical precision calibration
- Automatic wafer thickness measurement and ID reading card can be upgraded
- Leading internal anti - shock system device, more stable operation

2) X Series Semi-Automatic Probe Station

